

PATENT ABSTRACTS OF JAPAN

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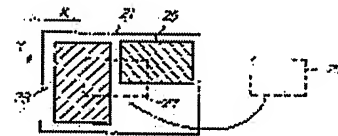
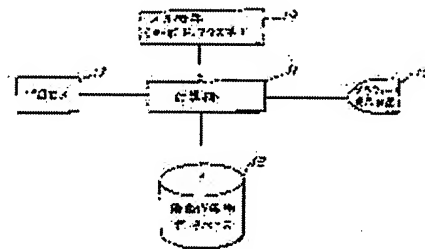
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(54) WINDOW SYSTEM FOR PLANT MONITORING DEVICE

(57)Abstract:

PURPOSE: To immediately reproduce and display an optimum window layout by generating a new window on a graphic screen by avoiding the overlap of respective windows and preserving and reproducing the window layout generated and the contents of the respective windows.

CONSTITUTION: An overlap avoiding means is provided in a computer 11 so as to prevent a window 27 displayed from overlapping with other windows 23 and 25 at the time of generating the window 27. When a state preservation request is made, the computer 11 informs a preservation request to a process where each window display processing is executed, so that the preservation processing of the state of the window is performed. Also, the computer 11 possesses a function reproducing the preserved window layout and screen images displayed on the respective windows. Thus, the optimum window layout is obtained per an individual plant monitor.



LEGAL STATUS

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1. 本発明は、半導体装置に関する。

図1
図2
図3

図4
図5
図6

図7
図8
図9

図10
図11
図12

図13

図14

図15
図16
図17

本発明は、半導体装置に関する。図1は、本発明の第1実施形態に係る半導体装置の平面図を示す。図2は、図1の半導体装置の断面図を示す。図3は、図1の半導体装置の他の断面図を示す。図4は、図1の半導体装置の他の断面図を示す。図5は、図1の半導体装置の他の断面図を示す。図6は、図1の半導体装置の他の断面図を示す。図7は、図1の半導体装置の他の断面図を示す。図8は、図1の半導体装置の他の断面図を示す。図9は、図1の半導体装置の他の断面図を示す。図10は、図1の半導体装置の他の断面図を示す。図11は、図1の半導体装置の他の断面図を示す。図12は、図1の半導体装置の他の断面図を示す。図13は、図1の半導体装置の他の断面図を示す。図14は、図1の半導体装置の他の断面図を示す。図15は、図1の半導体装置の他の断面図を示す。図16は、図1の半導体装置の他の断面図を示す。図17は、図1の半導体装置の他の断面図を示す。

図18

図19

図20

図21

図22

図23

図24

図25

図26

図27

図28

図29

図30

図31

図32